## DT06 Rec'd PCT/PTO 0 1 MAR 2005

Sheet 1 of 1

**FORM PTO-1449** 

## U. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

## LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

CAPEWELL et al

FILING DATE GROUP 2822

March 1, 2005

Not yet assigned

**U.S. PATENT DOCUMENTS** 

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EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
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BA	АВ	5,410,167	04/25/95	Saito			
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BA	АН	EP 1 052 684 A1	11/15/00	European			xx		
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BA	AL "Molecular beam epitaxy of strained Si <sub>1.x</sub> Ge <sub>x</sub> layers on patterned substrates" 1993-06-01, Journal of Crystal Gro Holland Publishing Co., Vol. 130, nos. 3/4, pages 611-616, Bugiel et al.		
	AM		
	AN		
EXAMINER /Bac Au/		/Bac Au/	DATE CONSIDERED 05/23/2006
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